

Literatura:

- [1] Dekker, A.J.: Fyzika pevných látek. 1.vyd. Praha, Academia, 1966.
- [2] Dearnaley, G.; Northrop, D.C.: Semiconductor Counters for Nuclear Radiations., 2.ed. London, E. & F.N.SPON Ltd., 1964.
- [3] Knoll, G.F.: Radiation Detection and Measurement. 1.ed. New York, John Willey & Sons, 1979.
- [4] Blankenship, J.L. IEEE Trans. Nucl. Sci., NS 7, (2 - 3), 1960, s.190.
- [5] EG&G ORTEC, Oak Ridge, Tenn. 37830, USA: Product and Application Information "Instruments for Research and Applied Sciences". (B.r.)
- [6] Grew, G.W.: IEEE Trans. Nucl. Sci. NS 12, (1), 1965, s.308.
- [7] Sieffert, P. aj., IEEE Trans. Nucl. Sci., NS 14, (1), 1967, s.532.
- [8] Schmitt, H.W. aj., Bull. Am. Ph. Soc., 6, 1961, s.240.
- [9] ENERTEC, 67380 Lingolsheim, France: Passivated Ion Implanted Silicon Junction Detectors. (B.r.)
- [10] PGT, Princeton, N.J. 08540, USA: Product Information "Germanium and Silicon Photon Detectors". (B.r.)
- [11] Šeda, J.; Petr, I.; Sabol, J.: Detektory ionizujícího záření. 1.vyd. Praha, Vydavatelství ČVUT, 1977.
- [12] Love, T.A., aj., ORNL - 3016, 1960, s.280.
- [13] Huber, R.J. Trans. Am. Nucl. Soc., 7, 1964, s.368.
- [14] Dearnaley, G., Ferguson, T.G. Nucleonics, 20, No.4., 1962, s.84.
- [15] Pell, E.M. Journ. of Appl. Phys. 31, 1960, s.291.
- [16] Pehl, R.H., aj., IEEE Trans. Nucl. Sci., NS-26 N1, 1979, s.321.
- [17] Kraner, H.V., aj., IEEE Trans. Nucl. Sci., NS-22 N1, 1975, s.149.